Daesuk Kim

List of Publications by Year
in descending order

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42	690	687363	552781
papers	citations	13 h-index	26 g-index

42	42	42	294
all docs	docs citations	times ranked	citing authors

#	Article	IF	Citations
1	Dynamic spectroscopic imaging ellipsometry. Optics Letters, 2022, 47, 1129.	3.3	3
2	Speed enhancement of dynamic spectroscopic ellipsometry by using direct spectral phase extraction method. Applied Optics, 2021, 60, 10867.	1.8	0
3	Dynamic spectroscopic ellipsometry based on a one-piece polarizing interferometric scheme. Optics Communications, 2020, 454, 124426.	2.1	11
4	Direct Spatially Resolved Snapshot Interferometric Phase and Stokes Vector Extraction by Using an Imaging PolarCam. Chinese Physics Letters, 2020, 37, 074201.	3.3	0
5	One-piece polarizing interferometer for ultrafast spectroscopic polarimetry. Scientific Reports, 2019, 9, 5978.	3.3	11
6	Highly robust digital holographic polarization imaging. , 2019, , .		0
7	Real time polarization phase imaging based on off-axis digital holographic scheme. , 2019, , .		0
8	Interferometric snapshot spectro-ellipsometry. Optics Express, 2018, 26, 1333.	3.4	13
9	Direct spatially resolved snapshot polarimetric phase extraction by using an imaging PolarCam. , 2018, , .		0
10	Dynamic spectro-ellipsometry based on a spectral interferometric phase extraction method. , 2017, , .		0
11	Dynamic spectro-polarimeter based on a modified Michelson interferometric scheme. Optics Express, 2016, 24, 14419.	3.4	7
12	Robust snapshot interferometric spectropolarimetry. Optics Letters, 2016, 41, 2318.	3.3	15
13	Snapshot spectro-ellipsometry based on interferometric polarization modulation. , 2015, , .		0
14	Stokes vector measurement based on snapshot polarization-sensitive spectral interferometry. Optics Express, 2014, 22, 17430.	3.4	12
15	Snapshot full Stokes vector measurement based on spectral interferometry. , 2014, , .		0
16	Thermal analysis of high power LEDs on the MCPCB. Journal of Mechanical Science and Technology, 2013, 27, 1493-1499.	1.5	12
17	Complex object wave direct extraction method in off-axis digital holography. Optics Express, 2013, 21, 3658.	3.4	19
18	Calibration of a snapshot phase-resolved polarization-sensitive spectral reflectometer. Optics Letters, 2013, 38, 4829.	3.3	10

#	Article	IF	Citations
19	Temperature distribution measurement by using a single-shot normal incidence imaging ellipsometer scheme. , 2012, , .		1
20	Non-coherent noise reduction in digital holography based on root mean square technique. Optik, 2012, 123, 2131-2135.	2.9	1
21	An automatic processing technique for accurate surface form measurement. Optik, 2012, 123, 295-301.	2.9	3
22	Curvature measurement using phase shifting in-line interferometry, single shot off-axis geometry and Zernike's polynomial fitting. Optik, 2012, 123, 422-427.	2.9	13
23	Influence of the collimation of the reference wave in off-axis digital holography. Optik, 2012, 123, 1469-1473.	2.9	5
24	Real-time dual-wavelength digital holographic microscopy based on polarizing separation. Optics Communications, 2012, 285, 233-237.	2.1	26
25	Single-shot, dual-wavelength digital holography based on polarizing separation. Applied Optics, 2011, 50, 3360.	2.1	99
26	Two-wavelength in-line phase-shifting interferometry based on polarizing separation for accurate surface profiling. Applied Optics, 2011, 50, 6153.	2.1	60
27	Coherent noise suppression in digital holography based on flat fielding with apodized apertures. Optics Express, 2011, 19, 17951.	3.4	27
28	Snapshot phase sensitive scatterometry based on double-channel spectral carrier frequency concept. Optics Express, 2011, 19, 23790.	3.4	11
29	Radius of curvature measurement of spherical smooth surfaces by multiple-beam interferometry in reflection. Optics and Lasers in Engineering, 2010, 48, 643-649.	3.8	42
30	Direct filtering in phase contrast off-axis digital holography. , 2010, , .		0
31	Simultaneous measurement method of total and self-interference for the volumetric thickness-profilometer. Optics Express, 2009, 17, 1352.	3.4	9
32	A simple and quantitative alignment procedure between solid state cameras. Optics Express, 2009, 17, 23947.	3.4	4
33	3-D Nano Object Recognition by Use of Phase Sensitive Scatterometry. , 2009, , 493-501.		0
34	High speed volumetric thickness profile measurement based on full-field wavelength scanning interferometer. Optics Express, 2008, 16, 21022.	3.4	25
35	Efficient double-filtering with a single acousto-optic tunable filter. Optics Express, 2008, 16, 21505.	3.4	18
36	On-axis single shot digital holography using polarization based two sensing channels. , 2008, , .		1

#	Article	IF	Citations
37	Three-dimensional Nano-object Recognition by use of Phase Sensitive Scatterometry. AIP Conference Proceedings, 2007, , .	0.4	0
38	White light on-axis digital holographic microscopy based on spectral phase shifting. Optics Express, 2006, 14, 229.	3.4	17
39	Three-dimensional-object recognition by use of single-exposure on-axis digital holography. Optics Letters, 2005, 30, 236.	3.3	97
40	Direct spectral phase function calculation for dispersive interferometric thickness profilometry. Optics Express, 2004, 12, 5117.	3.4	31
41	Measurement of the thickness profile of a transparent thin film deposited upon a pattern structure with an acousto-optic tunable filter. Optics Letters, 2002, 27, 1893.	3.3	84
42	Distortion-Tolerant 3D Object Recognition by Using Single Exposure On-Axis Digital Holography. , 0, , 195-206.		3